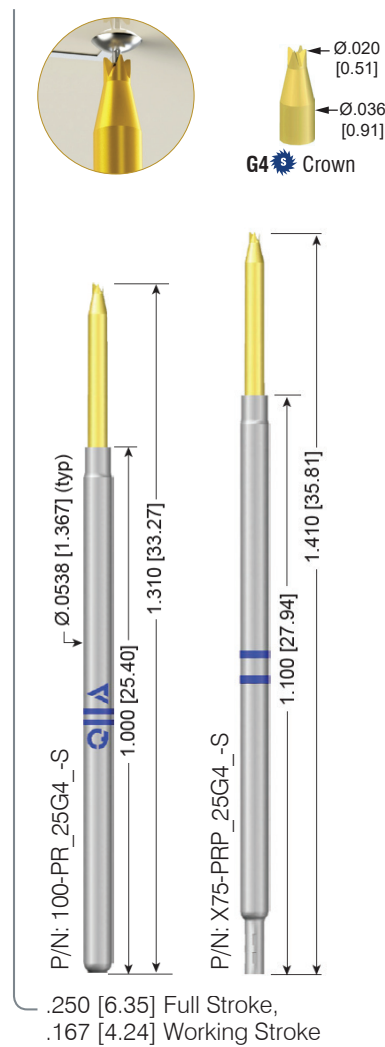


New Self-Cleaning G4 Crown Tip Style

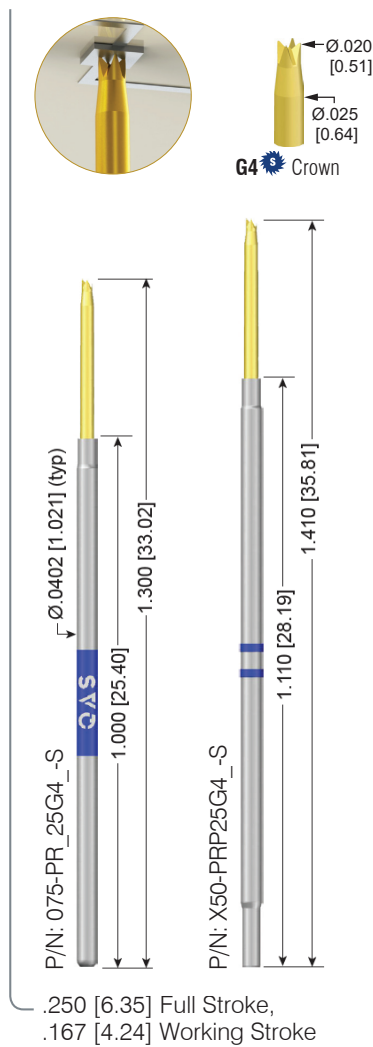
With today's complex printed circuit board processes, QA Technology continually works with customers to develop new solutions for contact challenges in their test environments.

Our new "G4" Crown tip style is a self-cleaning steel tip designed with 4 sharp cutting edges to contact solder domes and test pads. In addition, the inner 90° angle feature is also beneficial in capturing small short leads. This "G4" tip has a similar tip diameter across the 100, 75 and 50mil probe series, giving the advantage of the same tip geometry for a given contact feature on the Unit Under Test (UUT).

100-25 & X75-25 SERIES



075-25 & X50-25 SERIES



050-25 & X39-25 SERIES

